**UNIVERSIDADE FEDERAL DE MINAS GERAIS**
**ESCOLA DE ENGENHARIA**
**Programa de Pós-Graduação em Engenharia**
**Metalúrgica, Materiais e de Minas**
Av. Antônio Carlos, 6627 - Campus da UFMG - Pampulha
Escola de Engenharia - Bloco 2 - Sala 2230 - Belo Horizonte - MG - CEP 31270-901
Tel.: 31 3409-1801/3652 Fax: 31 3409-1815 *e-mail*: ppgem@demet.ufmg.br

# EMT901 - Caracterização de Superfícies e Interfaces

Análise e Caracterização de Materiais, Interfaces e Recobrimentos, Métodos de Caracterização e Análise, Métodos de Imagem, Microscopia óptica e eletrônica, Microscopia de Força Atômica, Métodos Espectroscópicos, Espectroscopia eletrônica, Vibracional e Rotacional, Técnicas de análise de superfícies, Aplicações das Técnicas de Análise de Superfícies e Interfaces, Análise de Falha e Defeitos, Processos Físico-Químicos.

Créditos: 04

Horas-aula: 60

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Periódicos: Materials Characterization; Polymer; Materials Chemistry and Physics - Elsevier; Journal of Materials Science; Nanoscale Research Letters - Springer; ACS journals; RSC journals;